App. No.: 10/606,897 Agilent Docket No.: 10030339-1

Art Unit: 2863

## **AMENDMENTS TO THE CLAIMS**

Please replace all prior versions of the claims with the following claim listing:

## Claims:

1-20. (Cancelled)

21. (New) A method comprising:

displaying a first waveform and a second waveform;

displaying a plurality of icons, each icon corresponding to a measurement to be performed of a parameter defining a relationship between the first waveform and the second waveform;

enabling a user to select one of the plurality of icons;

enabling the user to mark a first point on the first waveform;

enabling the user to mark a second point on the second waveform;

performing a measurement based on the selected icon, the first point on the first waveform, and the second point on the second waveform.

- 22. (New) The method of claim 21, wherein the parameter is one of a setup time, a hold-time, a time difference, and a phase difference.
  - 23. (New) The method of claim 22, further comprising: displaying the measured parameter.
- 24. (New) The method of claim 21, wherein enabling the user to mark the first and second points further comprises:

responding to a user-manipulated pointing device, the pointing device comprising one of a mouse, a joy-stick, a track-ball, a keyboard, a touch-screen, and a touch-pad.

25. (New) The method of claim 21, wherein enabling the user to mark the first and second points further comprises:

placing markers on the first and second points, the markers being similar in appearance to the selected icon.

App. No.: 10/606,897 Agilent Docket No.: 10030339-1

Art Unit: 2863

26. (New) The method of claim 21, wherein displaying the first and second waveforms further comprises:

receiving first and second signals from a device under test, the first and second signals corresponding to the first and second waveforms, respectively.

- 27. (New) The method of claim 21, further comprising: enabling the user to set a measurement threshold based on a percentage of change of one of the first and second waveforms.
- 28. (New) A measuring and testing instrument (MTI) comprising:
  a display device configured to display a first waveform, a second waveform,
  and a plurality of icons, each icon corresponding to a measurement to be performed of
  a parameter defining a relationship between the first waveform and the second
  waveform;

means for receiving user input, the user input corresponding to a selected first point on the first waveform, and a selected second point on the second waveform, and a selected icon; and

means for measuring a parameter based on the selected icon, the first point, and the second point.

- 29. (New) The MTI of claim 28, wherein the measured parameter is one of a set-up time, a hold-time, a delay, and a phase difference.
- 30. (New) The MTI of claim 29, wherein the display device is further configured to display the measured parameter.
- 31. (New) The MTI of claim 28, further comprising a pointing device allowing a user to select the first point on the first waveform, the second point on the second waveform, and one of the displayed icons
- 32. (New) The MTI of claim 31, wherein the pointing device is one of a mouse, a joy-stick, a track-ball, a keyboard, a touch-screen, and a touch-pad.

App. No.: 10/606,897 Agilent Docket No.: 10030339-1

Art Unit: 2863

33. (New) The MTI of claim 28, wherein the display device is further configured to display a first mark representing the selected first point on the first waveform and a second mark representing the selected second point on the second waveform.

- 34. (New) The MTI of claim 33, wherein the first and second marks are similar in appearance to the selected icon.
- 35. (New) The MTI of claim 28, further comprising an oscilloscope configured to receive the first and second waveforms from a device under test.
- 36. (New) A graphical user interface (GUI) for use with a measurement device, the GUI comprising:

a waveform display region for displaying a first waveform and a second waveform; and

a toolbar region for displaying a plurality of icons, each icon corresponding to a measurement to be performed of a parameter defining a relationship between the first waveform and the second waveform;

wherein, by manipulation of a pointing device, a first marker is displayed on a first point of the first waveform and a second marker is displayed on a second point of the second waveform.

- 37. (New) The GUI of claim 36, further comprising an information region for displaying a type of measurement being performed based on a selected icon.
- 38. (New) The GUI of claim 36, further comprising a result region for displaying results of a measurement.
- 39. (New) The GUI of claim 36, wherein the first and second markers are positioned over the first and second waveform, respectively, by a drag-and-drop process.